## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of: Chuan Hu and Daoqiang Lu

Serial No. Not yet assigned

Filed: Concurrently herewith

For: FLUXLESS DIE-TO-HEAT SPREADER BONDING USING THERMAL

INTERFACE MATERIAL

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Applicant submits herewith PTO Form 1449 listing patents and publications of which he is aware which may be material to the examination of this application and in respect of which there may be a duty to disclose in accordance with 37 CFR Section 1.56.

The above-referenced application is a divisional of U.S. Serial No. 10/436,677, filed May 12, 2003. It includes the same disclosure as U.S. patent application Serial No. 10/436,677.

It is understood that the listed references will be considered in the examination of the application and that no separate copies of the same prior art are required to be provided since they were previously cited or transmitted in the foregoing prior application. 37 CFR Section 1.98(d). Form(s) PTO 1449 is enclosed listing references cited by the Examining Attorney and submitted by applicant in the prior applications.

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Respectfully submitted,

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## INFORMATION DISCLOSURE CITATION FORM PTO-1449 (Modified)

## **U.S. PATENT DOCUMENTS**

Exam <u>Init</u>	<u>Ref</u>	Document Number 6,471,115 B1 6,495,397 B2	Issue <u>Date</u> 10/29/2002 12/17/2002	Name Ijuin et al. Kubota et al.	Class	Sub <u>Class</u>
FOREIGN PATENT DOCUMENTS						
Exam <u>Init</u>	<u>Ref</u>	Document <u>Number</u>	Publication Date	Country	<u>Name</u>	
OTHER DOCUMENTS						
Exam Init Ref Author, Title, Date, Pertinent Pages, Etc.) Klink et al., "Innovative Packaging Concepts for Ultra Thin Integrated Circuits," IEEE 2001 Electronic Components and Technology Conference, 5 pages (2001).  Dodd et al., "Impact of Substrate Thickness on Single-Event Effects in Integrated Circuits," IEEE Transactions on Nuclear Science, Vol. 48, No. 6, p. 1865-1871 (December 2001).  Sunohara et al., "Development of Wafer Thinning and Double-Sided Bumping Technologies for the Three-Dimensional Stacked LSI," IEEE 2002 Electronic Components and Technology Conference, p. 238-245 (2002). http://www.webelements.com/webelements/text/Au/enth.html, Mark Winter, The University of Sheffield, 4 pages (3/6/2003).  "Some Practical Suggestions for Solder Preform Design," Indium Corporation of America, 1 page (prior to 5/12/03).  "Mechanical Enabling for the Intel® Pentium® 4 Processor in the 478-Pin Package," Intel Corporation (October 2001).						
Examiner:						
Date Considered:						